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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(213.003-D2-US)

In re Application of: Ye et al.

Serial No: 10/763,142

Filed: January 22, 2004

Title: Method and Apparatus for Monitoring
Integrated Circuit Fabrication

Group Art Unit: 2125

Examiner:

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

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Michael Siter
(person signing this certificate)
Michael Siter
Signature

THIRD INFORMATION DISCLOSURE STATEMENT

Dear Sir:

Submitted herewith is one (1) sheet of a modified Form PTO-1449. A copy of each
document cited on the attached Form PTO-1449 is also submitted.

It is respectfully requested that the Examiner make his/her consideration of these
references formally of record with the initial Office Action.

Respectfully submitted,

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Date: July 30, 2004

Neil A. Steinberg
Neil A. Steinberg
Reg. No. 34,735
650-968-8079

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Sheet 1 of 1

PTO-1449 (Modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT	ATTY. DOCKET NO. 213.003-D2-US	SERIAL NUMBER 10/763,142
	APPLICANT(S) Ye et al.	
	FILING DATE January 22, 2004	GROUP ART UNIT 2125

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	5,444,637	8/1995	Smesny et al.			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	TRANSLATION YES/NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

EXAMINER	DATE CONSIDERED
EXAMINER: Initial citation if reference was considered. Draw line through citation if not in conformance to MPEP 609 and not considered. Include copy of this form with next communication to applicant.	

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE
(213.003-D2-US)**

APPLICANT: Ye et al.

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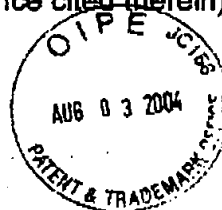
SERIAL NO.: 10/763,142

**TITLE: Method and Apparatus for Monitoring Integrated Circuit
Fabrication**

RECEIPT OF THE FOLLOWING PAPERS IS ACKNOWLEDGED

1. Third Information Disclosure Statement (1 page + Modified Form-PTO-1449 (1 page) + Reference cited therein)

DATE: July 30, 2004



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